

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	09/725,672	HANEDA ET AL.
	<b>Examiner</b> Philip C. Lee	<b>Art Unit</b> 2154

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Google Search	5/20/2005	PL
ACM Search	5/20/2005	PL
IEEE Search	5/20/2005	PL
Keywords Search in EAST	5/20/2005	PL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
709	240	5/20/2005	PL
709	253	5/20/2005	PL
370	472	5/20/2005	PL
370/437		5/20/2005	PL